Search Notes		

Application/Control No.	Applicant(s)/Patent un Reexamination	nder
10/646,324	CHEN ET AL.	
Examiner	Art Unit	
Trenton J. Roche	2193	

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717	168-173 (text search)	11/30/2006	TR
714	(text)	12/26/2006	TR
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE -	
Inventor Search	12/19/2006	TR
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